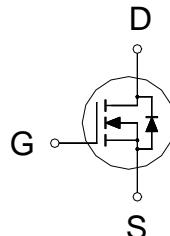


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV _{DSS}	80V
R _{DSON} (MAX.)	65mΩ
I _D	6A



UIS, 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V _{GS}	±20	V
Continuous Drain Current	T _A = 25 °C	I _D	6	A
	T _A = 100 °C		4.5	
Pulsed Drain Current ¹		I _{DM}	24	
Avalanche Current		I _{AS}	7	
Avalanche Energy	L = 0.1mH, ID=7A, RG=25Ω	E _{AS}	2.45	mJ
Repetitive Avalanche Energy ²	L = 0.05mH	E _{AR}	1.23	
Power Dissipation	T _A = 25 °C	P _D	2.5	W
	T _A = 100 °C		1	
Operating Junction & Storage Temperature Range		T _j , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	6	50	°C / W
Junction-to-Ambient ³	R _{θJA}			

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

³50°C / W when mounted on a 1 in² pad of 2 oz copper.

ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	80			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.0	1.7	3.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 64V, V_{GS} = 0V$			1	μA
		$V_{DS} = 60V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 5V, V_{GS} = 10V$	6			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 6A$		55	65	$\text{m}\Omega$
		$V_{GS} = 5V, I_D = 4A$		68	85	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 6A$		12		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 30V, f = 1\text{MHz}$		1110		pF
Output Capacitance	C_{oss}			60		
Reverse Transfer Capacitance	C_{rss}			51		
Total Gate Charge ^{1,2}	Q_g	$V_{DS} = 40V, V_{GS} = 10V, I_D = 6A$		15		nC
Gate-Source Charge ^{1,2}	Q_{gs}			1.7		
Gate-Drain Charge ^{1,2}	Q_{gd}			4.1		
Turn-On Delay Time ^{1,2}	$t_{d(\text{on})}$	$V_{DS} = 40V, I_D = 1A, V_{GS} = 10V, R_{GS} = 6\Omega$		10		nS
Rise Time ^{1,2}	t_r			8		
Turn-Off Delay Time ^{1,2}	$t_{d(\text{off})}$			18		
Fall Time ^{1,2}	t_f			6		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_S				2.3	A
Pulsed Current ³	I_{SM}				9.2	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{GS} = 0V$			1.2	V

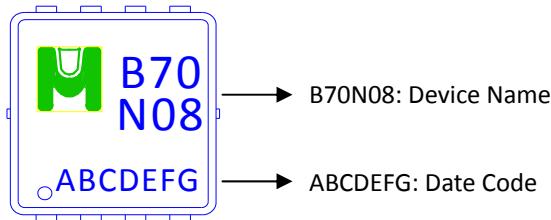
¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

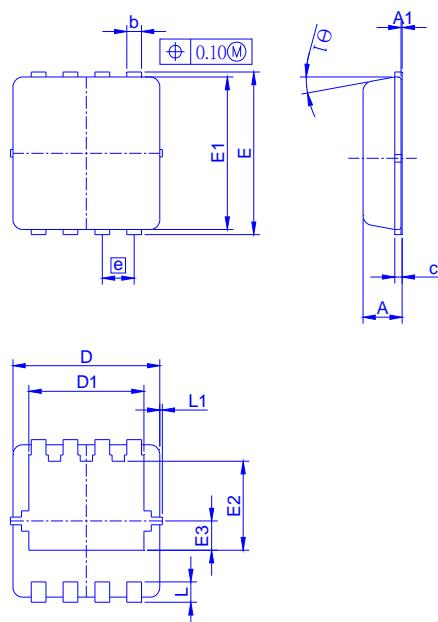
³Pulse width limited by maximum junction temperature.

Ordering & Marking Information:

Device Name: EMB70N08V for EDFN 3 x 3



Outline Drawing



Dimension in mm

Dimension	A	A1	b	c	D	D1	E	E1	E2	E3	e	L	L1	Θ1
Min.	0.70	0	0.24	0.10	2.95	2.25	3.15	2.95	1.65			0.30		0°
Typ.	0.80		0.30	0.152	3.00	2.35	3.20	3.00	1.75	0.575	0.65	0.40	0.13	10°
Max.	0.90	0.05	0.37	0.25	3.15	2.45	3.40	3.15	1.96			0.50		12°

Recommended minimum pads

